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| Notice of References Cited | | | Application/Control No. 10/789,504 | Applicant(s)/Patent Under Reexamination HSU ET AL. | |
| | | | Examiner Binh X. Tran | Art Unit 1792 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|-------------------------------|----------------|
| * | A US-5,145,889 | 09-1992 | Wada et al. | 523/451 |
| * | B US-2002/0022681 | 02-2002 | Ichiroku et al. | 524/261 |
| * | C US-2002/0077421 | 06-2002 | Sumita et al. | 525/107 |
| * | D US-2002/0089071 | 07-2002 | Sumita et al. | 257/793 |
| * | E US-2003/0071368 | 04-2003 | Rubinsztajn, Małgorzata Iwona | 257/793 |
| F | US- | | | |
| G | US- | | | |
| H | US- | | | |
| I | US- | | | |
| J | US- | | | |
| K | US- | | | |
| L | US- | | | |
| M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| N | | | | | |
| O | | | | | |
| P | | | | | |
| Q | | | | | |
| R | | | | | |
| S | | | | | |
| T | | | | | |

NON-PATENT DOCUMENTS

| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | |
|---|---|--|
| U | | |
| V | | |
| W | | |
| X | | |

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